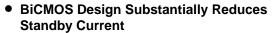
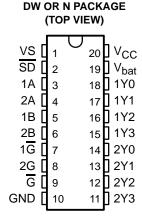
SN74BCT2414 MEMORY DECODER WITH ON-CHIP SUPPLY VOLTAGE MONITOR

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- Two Independent 2-Line to 4-Line Decoders or One 3-Line to 8-Line Decoder
- Separate Enable Inputs for Easy Cascading
- Two Supply Voltage Terminals (V_{CC} and V_{bat})
- Built-In Supply-Voltage Monitor for V_{CC}
- Automatic Cut Off of Outputs During V_{CC} Fail
- Package Options Include Plastic Small-Outline (DW) Packages and Standard Plastic 300-mil DIPs (N)



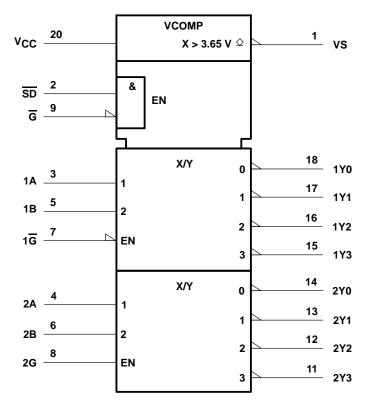
description

The SN74BCT2414 is a decoder specially designed to be used in memory systems with battery backup during power failure. The two independent 2-line to 4-line decoders with separate and common control inputs may be externally cascaded to implement a 3-line to 8-line decoder.

The circuit has two supply voltage inputs: the voltage monitor (bandgap) is powered via the V_{CC} terminal; the internal logic of the circuit is powered via the V_{bat} terminal. In case V_{CC} drops below 3.65 V (nominal), the voltage monitor forces the voltage-control (VS) and decoder outputs (Y) to the high level. VS may be used to disconnect the supply voltage of the memories (V_{bat}) from the system supply. This output is switched off when the on-chip supply voltage monitor detects a power failure.

The SN74BCT2414 is characterized for operation from 0°C to 70°C.

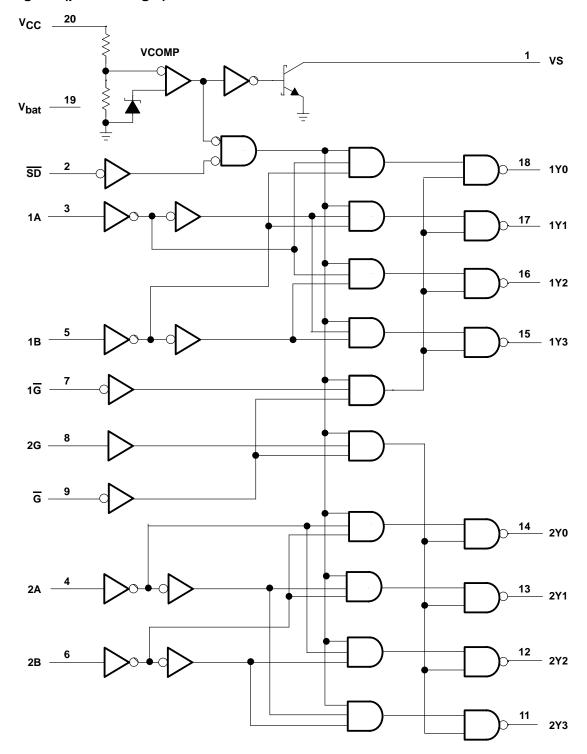
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)





FUNCTION TABLES

INPUTS					OUTPUTS				
С	CONTROL			ECT] 0017015				
G	1 G	SD	1B	1A	1Y0 1Y1 1Y			1Y3	
Н	Х	Χ	Х	Χ	Н	Н	Н	Н	
Х	Н	Χ	Х	Χ	Н	Н	Н	Н	
Х	Χ	L	Х	Χ	Н	Н	Н	Н	
L	L	Н	L	L	L	Н	Н	Н	
L	L	Н	L	Н	Н	L	Н	Н	
L	L	Н	Н	L	Н	Н	L	Н	
L	L	Н	Н	Н	Н	Н	Н	L	

INPUTS					OUTPUTS					
С	ONTRO	DL	SEL	ECT		0011	PU13			
G	2G	SD	2B	2A	2Y0	2Y1	2Y2	2Y3		
Н	Х	Х	Х	Х	Н	Н	Н	Н		
Х	Н	Χ	Х	Χ	Н	Н	Н	Н		
Х	Χ	L	Х	Χ	Н	Н	Н	Н		
L	Н	Н	L	L	L	Н	Н	Н		
L	Н	Н	L	Н	Н	L	Н	Н		
L	Н	Н	Н	L	Н	Н	L	Н		
L	Н	Н	Н	Н	Н	Н	Н	L		

NOTE: For a 3-line to 8-line decoder, the following pins must be shorted: 1G to 2G, 1A to 2A and 1B to 2B.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{bat}	
Supply voltage range, V _{CC}	0.5 V to 7 V
Supply voltage V _{CC} with respect to V _{bat}	–1.5 V
Input voltage range, V _I	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Off-state output voltage range at VS	0.5 V to 7 V
Voltage range applied to any Y output in the power-off state	0.5 V to 7 V
Voltage applied to any Y output in the power-off state with respect to V _{bat}	0.5 V
Operating free-air temperature range	0°C to 70°C
Storage temperature range	−65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability

recommended operating conditions

			MIN	NOM	MAX	UNIT
Vcc	V _{CC} Supply voltage			5	5.5	V
V _{bat}	Supply voltage		4.5	5	5.5	V
VIH	V _{IH} High-level input voltage					V
V _{IL}	V _{IL} Low-level input voltage				0.8	V
liK	I _{IK} Input clamp current				-18	mA
lOH	High-level output current	ut current			-400	μΑ
la.	Low-level output current	Y outputs			8	mA
IOL	VS outputs				20	IIIA
t _t	Input transition time		0		10	ns/V
TA	Operating free-air temperature		0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TES	T CONDITIONS	MIN	TYP [†]	MAX	UNIT
VIK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2	V
		V: V== 45V	$I_{OH} = -20 \mu A$	4.4			
V_{OH}		$V_{\text{bat}} = V_{\text{CC}} = 4.5 \text{ V}$	$I_{OH} = -400 \mu A$	3.5			V
		$V_{\text{bat}} = 2 \text{ V}, V_{\text{CC}} = 0,$	$I_{OH} = -50 \mu A$	1.8			
	All except VS	V:Voo-45V	I _{OL} = 4 mA			0.4	
VOL)L	$V_{\text{bat}} = V_{\text{CC}} = 4.5 \text{ V}$	I _{OL} = 8 mA			0.5	V
	VS	$V_{\text{bat}} = V_{\text{CC}} = 4.5 \text{ V},$	$I_{OL} = 20 \text{ mA}$			1	
V _T ‡					3.65		V
II		$V_{bat} = V_{CC} = 5.5 V,$	V _I = 5.5 V			100	μΑ
lн		$V_{bat} = V_{CC} = 5.5 V,$	V _I = 2.7 V			±20	μΑ
Iμ		$V_{\text{bat}} = V_{\text{CC}} = 5.5 \text{ V},$	V _I = 0.5 V			±20	μΑ
loh	VS	$V_{\text{bat}} = 4.5 \text{ V},$	VCC = 0			1	μΑ
IO§		$V_{\text{bat}} = V_{\text{CC}} = 5.5 \text{ V},$	V _O = 2.25 V	-30		-200	mA
la a		V V 55V	Outputs high			3	mA
ICC		$V_{\text{bat}} = V_{\text{CC}} = 5.5 \text{ V}$	Outputs low			3	mA
		$V_{\text{bat}} = 2.5 \text{ V},$	V _{CC} = 0		1	10	
l _{bat}	VS T [‡] H - DH VS S S CC at i Any Y	V V	Outputs high			20	μΑ
		$V_{\text{bat}} = V_{\text{CC}} = 5.5 \text{ V}$	Outputs low			3	mA
Ci		$V_{\text{bat}} = V_{\text{CC}} = 5 \text{ V},$	V _I = 0 or 3 V		4		pF
	Any Y	V ₁ V ₂ - 0			6.5		nE.
Co	VS	$V_{\text{bat}} = V_{\text{CC}} = 0$			5		pF

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

 $[\]ddagger$ This value represents the $\overrightarrow{V_{CC}}$ monitor threshold voltage. Typical range is from 3.5 V to 3.8 V.

[§] This output condition has been chosen to produce a current that closely approximates one half of the short-circuit output current, IOS. Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

switching characteristics (see Note 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 5 V, C_L = 50 pF, $R1$ = 500 Ω , $R2$ = 500 Ω , T_A = 25°C		V _{CC} = 4.5 C _L = 50 pF R1 = 500 Ω R2 = 500 Ω T _A = MIN to	;, <u>2</u> , <u>2</u> ,	UNIT	
t _{PLH}	A or B		1	5	10	1	12	
tPHL		Any Y	2	5.8	10	2	12	ns
t _{PLH}	Any G	Any V	1	4.5	9	1	10	ns
tPHL	Any G	Any Y	2	5.5	9	2	11	115
t _{PLH}	SD	Any V	2	6.5	11	2	12	ns
^t PHL	3D	Any Y	2	6.5	11	2	12	115

switching characteristics (see Note 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 5 V, C_L = 50 pF, R1 = 500 Ω, R2 = 500 Ω, T_A = 25°C		V_{CC} = 4.5 Ω C_L = 50 pF R1 = 500 Ω R2 = 500 Ω T_A = MIN to	, ,	UNIT	
			MIN	TYP	MAX	MIN	MAX	
^t PLH	Vaa	CC Any Y	10	25	50	10	250	ns
t _{PHL}	√cc		15	45	100	15	250	115
tPLH	Voc	vcc vs	10	28	50	10	250	ns
^t PHL] vcc		20	50	100	20	250	115

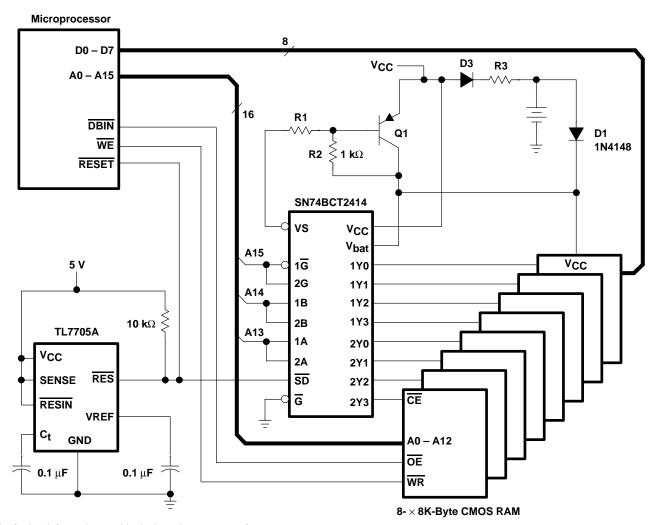
[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 1: Load circuits and voltage waveforms are shown in Section 1.



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APPLICATION INFORMATION

A typical application circuit for a battery-buffered memory in a microcomputer system is shown in Figure 1 which uses the SN74BCT2414. When power fails, the supply-voltage supervisor (TL7705) resets the microcomputer and disables the memory by switching the shutdown input \overline{SD} of the memory decoder to a logic zero. All memory decoder outputs are forced to a logic one. Abnormal write commands from the microprocessor, which may be issued during further voltage breakdown, no longer affect the contents of the memory. When the system supply voltage becomes lower than approximately 3.65 V, the voltage monitor inside the SN74BCT2414 memory decoder disconnects the input buffers of this circuit from the decoding logic internally and keeps all outputs at a logic one. The VS output is also switched off, disconnecting the system supply voltage from the memory circuits. During this low-voltage condition, the memory decoder and the memory circuits are supplied by the battery.



For further information on this device, please contact factory.

Figure 1. Memory System With Battery Backup



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